

Application/Control No.	Applicant(s)/Patent under Reexamination
10/587,576	NAKAYAMA ET AL.
Examiner	Art Unit
Hai H. Huynh	3747

OFAROUSE							
SEARCHED							
Class	Subclass	Date	Examiner				
123	435-436	11/7/2007	ннн				
701	110-111	11/7/2007	ннн				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
above	search	11/7/2007	ннн		
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(INCLUDING SEARCH STRATEGY)					
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